

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:)	
)	Examiner: Bradley K. Smith
Chau, et al.)	
)	Art Unit: 2891
Application No: 10/760,028)	
)	Atty Docket No.: 42P17814
Filed: January 16, 2004)	
)	Confirmation No.: 8503
For: TRI-GATE TRANSISTORS AND)	
METHODS TO FABRICATE SAME)	
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Mail Stop Issue Fee

Assistant Commissioner For Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT AFTER ALLOWANCE

In accordance with Applicant's duty of disclosure, this Information Disclosure Statement, substitute for form 1449A/PTO (based on PTO/SB/08A), and cited reference(s) are being submitted after allowance of this application but prior to payment of the Issue Fee. It is respectfully requested that the cited reference(s) be placed in the file and that the subject application not be withdrawn from issue.

The fee set in the amount of \$180.00 for submission of the Information Disclosure Statement is enclosed herewith.

The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material to patentability.

Filed via EFS Web – July 5, 2007

The Commissioner is authorized to charge any deficiencies or credit any overpayments in connection with this submission to Deposit Account No. 02-2666, and is requested to notify us of same.

Respectfully submitted,
BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN, LLP

Date: July 5, 2007 /James M. Howard/
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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/760,028
Filing Date	January 16, 2004
First Named Inventor	Jin, Been-Yih
Group Art Unit	2891
Examiner Name	Smith, Bradley

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EXAMINER**DATE CONSIDERED**

Based on PTO/SB/06/09-06 - Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 02/26/07

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Examiner Name	Smith, Bradley

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OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

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